

v1.9		23-Sep-05		STEREO/ IMPACT Requirements Verification Matrix												
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments	
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2				
1.0		SCIENCE REQUIREMENTS														
1.1	MAG Science Requirements	Noise Level < 0.05nT	MRD - 4.7(K) and solar wind characteristics. IPF - 3.1			T						Apr-04	May-04	Pass	GSFC / Acuna	
1.2		Absolute Accuracy < +/- 0.1nT	MRD - 4.7(K) IPF - 3.1			S,T						Apr-04	May-04	Pass	GSFC / Acuna	
1.3		Range = +/-512nT	MRD - 4.7(K) IPF - 3.1			T						Apr-04	May-04	Pass	GSFC / Acuna	
1.4		Drift < +/- 0.2 nT/yr	MRD 4.6,2.6.1 and Absolute Accuracy IPF - 3.1			S,T						Apr-04	May-04	Pass	GSFC / Acuna	
1.5		Time Resolution = 1 second	MRD - 4.7(K) IPF - 3.1						T			May-04	Aug-04	Pass	UCB / Curtis	Bench test of FM1/2 IDPU with ETU LVPS, ETU harness
1.6	SWEA Science Requirements	FOV = 360 X 60 degrees	MRD - 4.7(H,I,J) IPF - 3.2			T						Nov-03	May-04	Pass	CESR	
1.7		Resolution = 45 degrees	MRD - 4.7(H,I,J) IPF - 3.2			T						Nov-03	May-04	Pass	CESR	
1.8		Energy = 20 to 1000eV	MRD - 4.7(H,I,J) IPF - 3.2			T, A						Nov-03	May-04	Pass	CESR	
1.9		Energy Resolution (Telemetry) < 100%	MRD - 4.7(H,I,J) and solar wind characteristics IPF - 3.2			T						Nov-03	May-04	Pass	CESR	
1.10		Geometric Factor > 0.001 cm ² ster E(eV)	MRD - 4.7(H,I,J) and solar wind characteristics IPF - 3.2			T						Nov-03	May-04	Pass	CESR	
1.11		Max Count Rate (per 22.5 degree sector) > 1E5 counts/sec	MRD - 4.7(H,I,J) and solar wind characteristics IPF - 3.2			T						Nov-03	May-04	Pass	CESR	
1.12		Time Resolution = 1 minute	MRD - 4.7(H,I,J)						T			Oct-04	Feb-05	Pass	UCB / Curtis	
1.13	STE Science Requirements	FOV = 60 x 60 degree	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T, A						Apr-04	Aug-04	Pass	UCB	
1.14		Resolution = 60 x 20 degrees	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T, A						Apr-04	Aug-04	Pass	UCB	
1.15		Energy = 5 - 100 keV	MRD - 4.7(F,G) IPF - 3.3			T						Apr-04	Aug-04	Pass	UCB	
1.16		Energy Resolution (Telemetry) < 100%	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T						Jun-04	Aug-04	Pass	UCB	STE-U Thermal Vac tests
1.17		Energy Resolution (Electronic) < 2keV	IPF - 3.3			T						Apr-04	Aug-04	Pass	UCB	
1.18		Geometric Factor > 0.1 cm ² ster	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T,A						Apr-04	Aug-04	Pass	UCB	Use door source to verify geometric calculations
1.19		Background < 30c/s/detector	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T						Apr-04	Aug-04	Pass	UCB	
1.20		Max Count Rate (per detector) > 10,000 counts/sec	MRD - 4.7(F,G) and solar wind characteristics IPF - 3.3			T						Apr-04	Aug-04	Pass	UCB	
1.21		Time Resolution = 1 minute	MRD - 4.7(F,G) IPF - 3.3						T			Apr-04	Aug-04	Pass	UCB	STE-U FM1 Thermal balance, STE-U FM2 Thermal Vac
1.22	SIT Science Requirements	FOV = 17 x 44 degrees	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			A						Feb-05	Feb-05	Pass	Umd	
1.23		Energy = 30-2,000 keV/nuc He-Fe	MRD - 4.7(F,G) IPF - 3.4			A, T						Jan-05	Feb-05	Pass	Umd	Analysis of thin foil thickness (from manufacturer's specification), solid state detector threshold, and dynamic range of solid state detector energy amplifier and time-of-flight system. Spot-checks of performance done with radioactive alpha-sources, and ion beam calibration at Brookhaven Tandem Van de Graaff.

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1.24		Mass Resolution = 0.85 AMU (⁴ He at 1MeV/Nuc)	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			T						Laboratory calibration with radioactive alpha sources (energy approx 1 MeV/nucleon)	Jan-05	Feb-05	Pass	UMd	
1.25		Energy Resolution - 35keV FWHM @ 22C	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			T						Pulsar calibration of energy system, along with calibration using radioactive alpha sources.	Jan-05			UMd	need to verify FM2 with new SSD
1.26		Geometric Factor - 0.4 cm ² ster	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			A						Geometrical analysis of SIT telescope, thin foil and solid state detector size.	Feb-05	Feb-05	Pass	UMd	
1.27		Background = 10 ⁻² events/sec during vac test	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			T						Observe background event rate during lab vacuum tests without source.	Feb-05	May-05	Pass	GSFC/ UMd	Tested FM2 with new detector
1.28		Max Event Rate = 1000 events/sec	MRD - 4.7(F,G) and CME characteristics IPF - 3.4			T						Pulsar calibration of instrument, and calibration at tandem Van de Graaff at Brookhaven National Lab.	Aug-05	Aug-05	Pass	UMd	
1.29		Time Resolution = 15 minutes	MRD - 4.7(F,G) and CME characteristics IPF - 3.4						T			SEP Suite testing shall verify end-to-end throughput	Oct-05	Oct-05	Pass	CIT	meets goal of 1 minute
1.30	SEPT Science Requirements	FOV = 2 sets for electrons and protons, each with: 2 oppositely directed view cones in-ecliptic, 2 oppositely directed view cones off-ecliptic, 45 degree full opening angle.	MRD - 4.7(F,G) and CME characteristics IPF - 3.5			A						Geometrical analysis of SEPT telescope, collimator aperture, magnet air gap, thin foil, and solid state detector size.	Feb-04	Feb-04	Pass	Kiel	
1.31		Energy = 30-400 keV, electrons 60-2000 keV, protons	MRD - 4.7(F,G) IPF - 3.5			A, T						Analysis of vector field of magnetic remanence with point charge model approach. Spot-checks to verify analytical calculations.Measurement of foil thickness with alpha-spectrometer (50 nm resolution).Mathematical model of SEPT telescope (GEANT Monte-Carlo-Simulation). Verification of model with ion-source (up to 300 keV) at HMI, Tandem Van de Graaff (up to 7 MeV) at HMI, conversion electrons (up to 1 MeV) with radioactive sources	Feb-04	Feb-04	Pass	Kiel	Ion-source and Tandem van de Graaff only with flight spare later in 2005
1.32		Energy Resolution (Telemetry) = 30% electrons, 30% protons	MRD - 4.7(F,G) and CME characteristics IPF - 3.5			T						Measurement with cosmic ray muons, radioactive sources, proton beam, pulser calibration.	Dec 04	Dec 04	Pass	Kiel	Proton beam with flight spare later in 2005
1.33		Geometric Factor > 0.4 cm ² ster, electrons 0.4 cm ² ster, protons	MRD - 4.7(F,G) and CME characteristics IPF - 3.5			A						Geometrical analysis of SEPT telescope, collimator aperture, magnet air gap, thin foil, and solid state detector size. Monte-Carlo-Simulation to determine telescope response as function of energy and incidence angle.	Feb-04	Feb-04	Pass	Kiel	
1.34		Background < 2 counts/s on ground, 20 degrees C	MRD - 4.7(F,G) and CME characteristics IPF - 3.5			T						Measurement of background event rate during lab vacuum tests without source.	Mar 04	Mar 04	Fail	Kiel	Background rate at lowest energy threshold (20 KeV) > 2 counts/s, threshold will be adjusted (by upload) to allow scientifically meaningful measurement. 2 counts/s is not a strict requirement.
1.35		Max Event Rate > 25,000 counts/s at 2.2 MeV 250,000 counts/s at 55 keV	MRD - 4.7(F,G) and CME characteristics IPF - 3.5			T						Pulsar calibration of instrument, calibration at tandem Van de Graaff at HMI (Hahn-Meitner-Institut, Berlin).				Kiel	Van de Graaff test on ETU pending
1.36		Time Resolution = 60 seconds	MRD - 4.7(F,G) and CME characteristics IPF - 3.5						T			SEP Suite testing shall verify end-to-end throughput	Oct 04	Oct 04	Pass	CIT	
1.37	LET Science Requirements	FOV = 2 oppositely directed 100 x 30 degree fans	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T						Geometrical analysis of LET instrument coupled with laboratorymapping of solid state detector areas.	Jan-05	Jan-05	Pass	CIT	
1.38		Energy Range (MeV/nucleon) = H: 1.5 - 3 He: 1.5 - 13 O: 3 - 25 Fe: 3 - 25	MRD - 4.7(F,G) IPF - 3.6			T						detector thickness measurements	Jan-05	Jan-05	Pass	CIT	
												Pulsar and alpha-particle calibrations and heavy-ion range-energy relations.	Jan-05	Jan-05	Pass	CIT	
												Verification at particle accelerator.	Jan-05	Jan-05	Pass	CIT	
1.39		Geometric Factor cm ² ster = H, He: 0.5 6=Z=26: 2	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T			A			Geometrical analysis of LET instrument coupled with laboratorymapping of solid state detector areas.	Jan-05	Jan-05	Pass	CIT	
1.40		Element Resolution = Resolve H, He, C, N, O, Ne, Mg, Si, Fe	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T			A			Alpha-particle measurement of detector thickness uniformity coupled with Monte Carlo simulations.	Jan-05	Jan-05	Pass	CIT	
												Final verification at particle accelerator.	Jul-04	Jul-04	Pass	CIT	

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1.41		⁴ He Mass Resolution = 0.35 AMU	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T, A						Calibrations with alpha particle source and electronic pulser aided by analysis.	Jan-05	Jan-05	Pass	CIT	
1.42		Max Event Rate = 1000 events/sec	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T						Bench tests with pulser;	Jan-05	Jan-05	Pass	CIT	
						T						verification at particle accelerator.	Jan-05	Jan-05	Pass	CIT	
1.43		Energy Binning = 6 intervals per species for Z=2=3 intervals for H	MRD - 4.7(F,G) and CME characteristics IPF - 3.6			T, A						Pulser and alpha-particle calibrations supplemented by Monte-Carlo simulations.	Jan-05	Jan-05	Pass	CIT	
						T						Verification at particle accelerator.	Jan-05	Jan-05	Pass	CIT	
1.44		Species Binning = H, ³ He, ⁴ He, C, N, O, Ne, Mg, Si, Fe	Derived from element resolution above IPF - 3.6			T, A						Pulser and alpha-particle calibrations supplemented by Monte-Carlo simulations.	Jan-05	Jan-05	Pass	CIT	
						T						Verification at particle accelerator.	Jan-05	Jan-05	Pass	CIT	
1.45		Time Resolution = 15 minutes, 1 prioritized event/sec	MRD - 4.7(F,G) and CME characteristics IPF - 3.6							T		SEP Suite testing shall verify end-to-end throughput	Jan-05	Jan-05	Pass	CIT	
1.46		Beacon Telemetry = 1 minute for H, He, 6=Z=26	MRD - 6.7.1 and CME characteristics IPF - 3.6							T		SEP Suite testing shall verify end-to-end throughput	Jan-05	Jan-05	Pass	CIT	
1.47	HET Science Requirements	FOV (full angle) = 50 degree cone	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Geometric analysis	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.48		Energy Range (MeV/nucleon) = e: 1 - 6 H, He: 13 - 40 3He: 16 - 40 -30 to 80 for 6 = Z = 14	MRD - 4.7(F,G) IPF - 3.7									Monte Carlo simulation + on-board response tables	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.49		Geometric Factor, cm ² ster = 0.5	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Geometric analysis	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.50		Element Resolution, dZ (rms), for stopping particles = 0.2 for 1 = Z = 14	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Monte Carlo simulation	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.51		⁴ He Mass Resolution = 0.25 amu	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Monte Carlo simulation	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.52		Max Event Rate = 1000 events/sec	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Ru-106 source, pulser	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.53		Energy Binning = Six intervals per species	MRD - 4.7(F,G) and CME characteristics IPF - 3.7									Monte Carlo simulation	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.54		Species Binning = H, ³ He, ⁴ He, 6 = Z = 14, Electrons	Derived from Element resolution above IPF - 3.7									By design	Jan-05	Jan-05	Pass	GSFC / Tycho	
1.55		Time Resolution = 15 minutes, 0.3 prioritized event/sec	MRD - 4.7(F,G) and CME characteristics IPF - 3.7							T		By design	Jan-05	Jan-05	Pass	CIT	
1.56		Beacon Telemetry = 1 minute H, He, e	MRD - 6.7.1 and CME characteristics IPF - 3.7							T		By design	Jan-05	Jan-05	Pass	CIT	
1.57	BOOM Science Requirements	Magnetic field = < 1nT static, 0.05 nT dynamic at the MAG sensor	MRD - 4.7(K) IPF - 4.1			A, T						Materials analysis supplemented by part-level measurements for items close to the MAG sensor and assembly measurement for the rest	Feb-04	Feb-04	Pass	UCB	

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1.58		MAG distance from spacecraft > 3m	MRD - 4.7(K) and typical spacecraft magnetic characteristics IPF - 4.1			I						Mar-04	Mar-04	Pass	UCB / JM	
1.59		MAG distance from other boom mounted instruments > 1m	MRD - 4.7(K) and recent experience with SWEA-like instrument IPF - 4.1			I						Mar-04	Mar-04	Pass	UCB / JM	
1.60		MAG distance from boom harness = 20 cm	MRD - 4.7(K) and expected harness currents IPF - 4.1			I						Mar-04	Mar-04	Pass	UCB / JM	
1.61		MAG mounting bracket material = non-metallic	MRD - 4.7(K) and thermal current issues IPF - 4.1			I, T						Feb-04	Feb-04	Pass	UCB / JM	
1.62		Instrument Alignment (includes <0.25 degree spacecraft allocation for mounting, attitude knowledge, etc., leaving 0.75 degrees for MAG sensor mounting, boom deployment repeatability, etc.) = +/- 1 degree knowledge	MRD - 4.7(K) IPF - 4.1 ICD 2.1.3/6.2.2			T						Oct-03		Pass	UCB / JM	
						T							Jun-04	Aug-04	Pass	UCB / JM
1.63		SWEA FOV = > 80 % clear	MRD - 4.7 (H, I, J) IPF - 4.1			A						Aug-03	Aug-03	Pass	APL	
1.64		SWEA FOV = No sunlight in aperture during science modes	MRD - 4.7 (H, I, J), detector sensitivity to UV IPF - 4.1			A						Aug-03		Pass	UCB / JM	
1.65		Boom surface conductivity = <10K ohms bulk, <10E8 ohms/square	MRD - 4.7 (H,I, J), electrostatics IPF - 4.1			T						Jun-04	Aug-04	Pass	UCB / JM	
1.66		STE FOV = clear	MRD - 4.7 (F,G), scattered light sensitivity IPF - 4.1			I						CDR		Pass	APL	
1.67		STE FOV = 2-bounce system to detectors	MRD 4.7 (H,I,J), detector sensitivity to UV IPF - 4.1			A						Aug-03		Pass	UCB / PT	
1.68		STE Thermal = < 0C	MRD - 4.7 (F,G), STE detector noise IPF - 4.1			A, T						Apr-04		Pass	UCB / PT	STE-U FM1 thermal balance, Al Seivold's analysis
1.69	Boom Stiffness	The IMPACT Boom, in its deployed configuration, shall be designed such that the first flexible body mode has a frequency above 0.5 Hz.	ENV - 3.4.1.2 ICD - 6.4.2.1 IPF - 4.2			T		T				Jun-04	Aug-04	Pass	UCB / JM	
1.70	Overall Timing Accuracy	The S/WAVES and IMPACT instruments and spacecraft shall be designed to allow science data to be time-tagged with a relative timing accuracy of <1ms between the S/WAVES and IMPACT instruments.	MRD - 6.2.3							T		Aug-05			UCB / UMn / APL	Test performed 8/05. Pending analysis of results by SWAVES.
2.0		THERMAL REQUIREMENTS														
		Instruments shall design for solar distances detailed in Table 3.3.1-0 in order to cover a launch opportunity during any month of the year (except Dec 2005 and Dec 2006).														
		1. Instruments shall assume worst case solar flux values ranging from ~1653.8 W/m2 to ~1152.3 W/m2 in its thermal models/analyses.														
		2. Instruments shall assume for its thermal models/analyses that the maximum off pointing referenced to the probe-sun line is 5 degrees during anomalous operations (Earth Acquisition Mode), 5 arc-min during normal operation and up to 45 degrees off-pointing (maximum duration of 105 minutes) for transient operation.														
		3. Instrument thermal analyses shall use the	ENV - 3.3.1 ICD - 5.11/5.15/5.1.3.2/			SEP			A			CDR		Pass	GSFC / Hawk	
21	Instrument Subsystem Thermal Design															

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		margin or safety (MS) / margins of safety for yield strength (Y) and ultimate strength (U) are defined as follows: MSY = Margin of Safety on Yield Strength = Material Yield Strength - 1.0 > 0 1.3 x Applied Stress MSU - Margin of Safety on Ultimate Strength = Material Ultimate Strength - 1.0 > 0 1.4 x Applied Stress		MAG	A							CDR		Pass	GSFC / Acuna			
				SWEA	A				Analyzer			Nov-02		Pass	CESR	Structural Analysis, COMAT (CESR) doc 6032-TN-RL-001		
3.2	Instrument Stiffness	Instruments shall be designed such that primary structural vibration modes are above 50 Hz. The IMPACT Boom, in its deployed configuration, shall be designed such that the first flexible body mode has a frequency above 0.5 Hz.	ENV - 3.4.1.2 ICD - 6.1.3.2/6.4.2.1 IPF - 4.2	SEPT	A							Jan-03		Pass	Kiel	SEPT Structural Analysis Doc.No. TOS-MCS/2002/721/n		
				SIT	A								CDR		Pass	GSFC / SS		
				SEPC		A					SEP Central / HET / LET			CDR		Pass	GSFC / SS	
				IDPU	A								CDR		Pass	UCB		
				Boom	A/T			T			Including STE & SWEA pedestal. Part of boom deployment test procedure.		May-04	Aug-04	Pass	UCB/ JM	Analysis backed by post-deployment "twang" test; uses mass dummies for instruments	
				MAG	A								CDR		Pass	GSFC / Acuna	Heritage for MAG sensor	
				SWEA	A						Analyzer		Nov-02		Pass	CESR	Structural Analysis, COMAT (CESR) doc 6032-TN-RL-001	
3.3	Instrument Venting Requirements	Instruments shall be designed and analyzed to provide relief ports or otherwise withstand a maximum pressure rate change of 1.0 psi/sec. Pressure profile testing is considered optional.	ENV - 3.4.1.3 ICD - 6.1.3.2	SEPT	A							Feb-04		Pass	Kiel			
				SIT	A							CDR		Pass	GSFC / SS			
				SEPC		A				SEP Central / HET / LET		CDR		Pass	GSFC / SS			
				IDPU	A							CDR		Pass	UCB / HB			
				Boom	A							CDR		Pass	UCB / JM			
				STE	A							CDR		Pass	UCB / PT			
				MAG	A							CDR		Pass	GSFC / Acuna	Heritage for MAG sensor		
				SWEA	A							CDR		Pass	UCB / PT			
3.4	Instrument Shock Design and Test	Self-induced shock shall be considered in the design of instruments with deployables. If actuation of the device is used, this test shall be performed twice.	ENV - 3.4.1.4 ICD - 6.1.3.2	Boom				T	T	Boom deploy test (once with instruments; see waiver)					UCB	Done & measured for Qual mode boom; done for MAG and STE-U, but not SWEA. To be done on FM booms at S/C EMC deploy		
				SWEA	T					SWEA door open test part of the SWEA functional	Oct-04	Jan-05	Pass	UCB				
				SIT	T					SIT door open test part of the SIT functional	Jul-05	Jul-05	Pass	UMd				
				SEPT	T					SEPT door open test part of the SEPT functional	Jan-04	Jan-04	Pass	Kiel				

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3.10	Center of Mass	Component center of mass shall be established to an accuracy of +/-0.25 inches.	ENV - 3.4.4.2 ICD - 6.3.1.2	SIT	A											Umd CIT	to be done by analysis to be done by analysis
				BOOM			A	T				Mar-05	May-05	Pass	UCB		
				IDPU	T							Mar-05	May-05	Pass	UCB		
3.11	Moments of Inertia	Instrument moment of inertia calculations shall have 10% accuracy as a goal.	ENV - 3.4.4.3 ICD - 6.3.1.3	SEPT	A											Kiel	to be done by analysis
				SIT	A											Umd	to be done by analysis
				SEPC			A									CIT	to be done by analysis
				BOOM				T				Mar-05		Pass	UCB		
				IDPU	T							Mar-05		Pass	UCB		
Mechanical I/F Req.																	
3.12	Instrument Mounting Repeatability	All instruments that need to be removed and replaced after optical axis alignment shall provide means of preserving alignment on repeated mountings. IMPACT boxes (except IDPU) require +/-1 degree alignment and +/-1 degree knowledge.	ICD - 6.2.2		A										Pass	Kiel	
					A										Pass	Umd	
						A									Pass	GSFC	Alignment requirements can be met by mounting hole tolerance without need of alignment
							A								Pass	UCB	
					A										Pass	UCB	
3.13	Payload Instrument Mounting Surface	Instrument components shall provide a planar surface for mounting to the S/C. The surface shall be flat to less than 0.010 inches across the longest span of the instrument. The average surface roughness height rating shall not exceed 125 micro inches along the instrument's longest dimension.	ICD - 6.2.6	SEPT	I							N/A	N/A			Kiel	N/A for SEPT-E because of Uterm bushings
				SIT	I							N/A	N/A			Umd	Mounted on stand-offs
				SEPC		I						N/A	N/A			GSFC	Mounted on stand-offs
				BOOM	I							Mar-05	May-05	Pass	UCB		Per fabrication spec.
				IDPU	I							Mar-05	May-05	Pass	UCB		Per fabrication spec. APL test
3.14	Structural Model Test and Verification	IMPACT shall perform test and verification of the finite element model.	ICD - 6.4.2.3	BOOM	T							May-04	Aug-04	Pass	UCB		
3.15	Payload Instrument Identification and Marking	IMPACT shall be marked with appropriate (AXXX) identification. The markings shall be permanent, resistant to chipping and located away from points of physical wear.	ICD - 6.5.4	SEPT	I							Dec 04	Dec 04	Pass	Kiel		
				SIT	I							Aug-05	Aug-05	Pass	Umd		
				SEPC		I						Aug-05	Aug-05	Pass	GSFC		
				BOOM	I							Jan-05	Jan-05	Pass	UCB		
				IDPU	I							Jan-05	Jan-05	Pass	UCB		
3.16	Instrument Leakage	Leakage testing shall be conducted at the instrument level to demonstrate that leakage rates of sealed hardware are within the prescribed mission limits. Leakage rates need to be checked before and after stress-inducing portions of the verification program to disclose anomalies caused by the stress.	ENV - 3.4.5						I	N/A; no hermetically sealed units							
4.0 ELECTRICAL																	
4.1	Instrument Component Magnetic Objectives	GSFC supplied 'sniffing' hardware will be used to map the magnetic emissions of selected instrument components (prior to integration) which are expected to contribute to the magnetic field.	ENV - 3.5	SEPT	T					Possibly arrange for group screening during the SEP suite I&T prior to EMC?		Aug-05	Aug-05	Pass	Kiel		
				SIT	T							Aug-05	Aug-05	Pass	Umd		
				SEPC		T						Aug-05	Aug-05	Pass	CIT		
				SWEA						Tested separately due to its proximity to MAG		Mar-05	May-05	Pass	UCB		
				BOOM	T			T		Boom piece-parts close to MAG to be individually screened		Jun-04	Jun-04	Pass	UCB		
				IDPU	T							Feb-05	May-05	Pass	UCB		
Instrument Component Design Radiation Requirements																	
4.2	Total Ionizing Dose	All parts used for the spacecraft are required to survive a total ionizing dose of 8 krad (Si) without part failure. If it is necessary to use a part having a susceptibility of less than 8krads (Si), the part may be used if the criteria noted in the Environmental Spec are met.	MRD - 4.6.9.1.1 ENV - 3.9.1	A,T						All EEE parts verified to meet the radiation requirement by analysis or test. Results documented on the parts lists. SIT DTOF is a special case that was radiation tested at the board level				Pass	UCB		
4.3	Displacement Damage	Components shall withstand displacement damage associated with the proton fluence levels shown in figure 3.9.2-1.	ENV - 3.9.2	A,T						All EEE parts verified to meet the radiation requirement by analysis or test. Results documented on the parts lists.				Pass	UCB		
Single Event Effects																	
4.4	Single Event Latch-up	Parts susceptible to single event latch-up with linear energy transfer threshold less than 80 MeV-cm ² /mg shall not be used in spacecraft components without latch-up mitigation techniques. Analysis and mitigation are subject to approval through the GSFC STEREO Project Office. The single event environment is shown in figure 3.9.3-1.	ENV - 3.9.3.1	A, T						All EEE parts verified to meet the radiation requirement by analysis or test. In some cases latchup protection circuitry is used. Results documented on the parts lists.				pass	UCB		

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix														
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments		
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2					
4.5	Single Event Upsets	Single event upsets (SEU) shall not cause mission-critical failures, compromise spacecraft health or mission performance. System level SEU effects shall be considered, such that upsets do not cause uncorrectable errors that impact system performance. All parts must be reviewed for SEU, along with any mitigation schemes needed to meet the system-level performance requirements.	MRD - 4.6.9.1.2 ENV - 3.9.3.2	A	T										Pass	UCB	
4.6	Single Event Upsets due to Heavy Ions	Calculation of upset rates due to heavy ions is required. If the part falls below a threshold of 15 MeV-cm ² /mg then guidance given in section 3.9.3.4 shall be followed.	ENV - 3.9.3.3	A	T										Pass	UCB	
4.7	Single Event Upset due to Protons	Parts with heavy ion upset thresholds below 15 MeV-cm ² /mg are considered susceptible to upsets due to protons. If such parts are used in components, proton testing and proton upset rate calculations shall be performed and summed with the upset rate due to heavy ions (section 3.9.3.3).	ENV - 3.9.3.4	A	T										Pass	UCB	
4.8	Upset Rates: Maximum Values	If it is necessary to use a part which has a high probability of experiencing upset during the mission time frame, component-level single event upset mitigation techniques shall be used with these parts.	ENV - 3.9.3.5	A	T										Pass	UCB	
4.9	EMC Design Rules and Requirements																
4.10	Primary Power Bus I/F	Primary power input lines and in-line heater circuits shall be electrically isolated within IMPACT by at least 1 Mohms from: 1) each other (unless internally switched or controlled) 2) chassis ground 3) all secondary circuits IMPACT shall be designed to support the voltage ranges specified in table 3.2 in the ICD /Power Bus	EMC - 3.2.1.1 ICD - 3.2.2 (Table 3-2)	SEP			T				Ground Isolation Test at SEP Suite I&T	Oct-05	Aug-05	Pass	CIT		
				IDPU			T				IDPU/MAG/STE-U Ground Isolation Test	Oct-04	Jan-05	Pass	UCB		
				SWEA			T				SWEA/STE-D Ground Isolation Test	Jan-05	May-05	Pass	UCB		
4.11	Primary Power Bus I/F	Components bridging this isolation I/F shall, as a minimum, be sized to withstand a potential difference of 100Vdc.	EMC - 3.2.1.1						A	LVPS design	Oct-04		Pass	UCB			
4.12	Primary Power Bus I/F Power Turn-On Transients	Primary power turn-On input current transients @ 28Vdc input from a source impedance of less than 200 mOhms shall not exceed 2.5 times the nominal current experienced in the highest power operating mode at 28Vdc (but excluding heater current) or, 2.5 amperes peak, whichever is greater. All components shall test to the limits discussed in section 3.10.2 and section 3.10.3 of the Environmental Spec. IMPACT shall conduct a turn-on/off transient tests to demonstrate compliance with primary power bus interface load transient requirements so as not to stress S/C power switching components, fuses, or interfere with S/C performance. A) The test power source must have a low transient impedance (to be achieved with a 10,000 uF or greater capacitor) B) A power switch exhibiting less than 20 mOhms insertion resistance together with bounceless closure characteristics and no transient limiting properties is to be used for turn-on measurements. C) A power switch incorporating no voltage limiting or any type of transient limiting characteristics is to be used for turn-off measurements.	ENV - 3.10.2/3.10.3 EMC - 3.2.1.3/4.11 ICD - 3.2.2.3	SEP			T				Primary Power Test at SEP Suite I&T	Jul-05	Jul-05	Pass	CIT	UCB can provide support for this test to CIT	
				IDPU			T					IDPU/MAG/STE-U Primary Power Test	Oct-04	May-05	Pass	UCB	
				SWEA			T					SWEA/STE-D Primary Power Test	Oct-04	May-05	Pass	UCB	
4.13	Primary Power Bus I/F	In all cases, the input current shall settle to within 10% of nominal current within 200 milliseconds after turn-on.	ENV - 3.10.2/3.10.3 EMC - 3.2.1.3 ICD - 3.2.2.3				T				Included in Primary Power test, 4.12						
4.14	Primary Power Bus I/F Power Turn-Off Transients	Primary power turn-OFF voltage transients appearing across IMPACT's power input terminals shall not exceed the range from +56 to -2 volts (absolute).	ENV - 3.10.4 EMC 3.2.1.4				T				Included in Primary Power test, 4.12						

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix															
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date				Notes / Comments			
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2	Results (Pass/Fail)	Responsible Organization				
4.15	Primary Power Bus I/F Ripple and Transient Currents	Infrequent and short-term Ripple and transient currents appearing at the primary power I/F as a consequence of motor operation, mode changes, or other operating characteristics, shall not exceed a peak-to-peak value of a) 0.7 times the nominal operating current, or b) 0.5 amperes, whichever is greater, as observed in the time domain using a bandwidth of at least 50MHz	ENV - 3.10.3 EMC - 3.2.1.5			T												
4.16	Primary Power Bus I/F	IMPACT shall be capable of surviving any primary power input voltage between 0 and +40Vdc, applied in any sequence, for an indefinite time.	EMC - 3.2.1.6			T												
4.17	Primary Power Bus I/F	IMPACT shall be capable of surviving a hard short circuit (for a duration of 10 msec) across the primary power input lines applied during operation. (possible reverse input current). Components shall provide assurance tha the stored charge of their instrument (i.e., the outrush current) will not blow fuses in the event of a hard short on the power bus.	ENV - 3.10.7 EMC - 3.2.1.7			T												
4.18	Primary Power Bus I/F	All primary power input lines are to self-discharge to less than 5Vdc within 2 seconds after power removal.	EMC - 3.2.1.8			T												
4.19	Primary Power Bus I/F	DC/DC power converters throughout the S/C shall be operated at 50KHz, or harmonic thereof, with a frequency tolerance of 100ppm over all environmental conditions.	EMC - 3.2.1.10	SEP	T					Measured in SEP LVPS functional test	Jun-04	Jul-04	Pass	UCB				
				IDPU	T					Measured in IDPU LVPS functional test	Jul-04	Aug-04	Pass	UCB				
				SWEA	T					Measured in SWEA LVPS functional test	Jul-04	Aug-04	Pass	UCB				
				SIT	T					Measured in SIT HVPS functional test	Dec-03	Dec-03	Pass	UCB				
				SWEA	T					Measured in SWEA HVPS functional test	Sep-03	Oct-03	Pass	CESR				
4.20	Removal of Instrument Power	The Instruments shall handle a warning message from the S/C prior to instrument safing/shutdown. IMPACT shall be designed to safe itself within 90 seconds after receiving a power shutdown warning message over the 1553 bus.	MRD - 4.6.8 ICD - 3.2.2.9	IDPU	T				IDPU software acceptance tests and IDPU functional tests shall verify correct handling of 1553 shutdown messages.	Oct-03		Pass	UCB					
4.21	Instantaneous Removal of Instrument Power	The Instruments shall be designed to withstand an instantaneous removal of power without a warning message from the S/C.	MRD - 4.6.8 ICD - 3.2.2.9	IDPU			T		IDPU Functional (with MAG & STE-U Instruments)	Oct-04	May-05	Pass	UCB					
				SEP			T		SEP Suite Functional	Aug-05	Aug-05	Pass	CIT					
				SWEA			T		SWEA/STE-D Functional	Oct-04	May-05	Pass	UCB					
4.22	One-Time Activation Electrical Characteristics	IMPACT doors and Boom release actuators shall be designed to receive a 100ms, +28V pulse, off unregulated power. All SMAs shall have auto-cutoff capability. IMPACT shall be designed to receive only 1 command service from the S/C for each of the redundant door unit circuits for SIT, SEPT-E(2x) and SEPT-NS(2x). Both sets of wires provided by the S/C shall be wired to the primary firing circuit for these actuators.	ICD - 3.2.3.1/3.2.3.2	SEPT		I, T					Mar 04	Mar 04	Pass	Kiel				
				SIT		I, T			During cold thermal balance	Feb-05	Mar-05	Pass	UMd			Test actuation time at worst case voltage, auto-cutoff, wire redundancy		
				Boom		I, T				May-04	Aug-04	Pass	UCB					
4.23	Electrical Bonding	Mounting surfaces of each unit shall be clean and free of paint or other insulating material and shall be capable of providing a DC bond resistance of no greater than 2.5mOhms when mounted to the next larger assembly structure. DC resistance measurements between any two adjacent exterior case parts shall not exceed 2.5 mOhms.	EMC - 3.2.3.1/3.2.3.2 ICD - 6.2.4	SEP		T			Bonding measurements at SEP I&T (ground strap)	Oct-04	Aug-05	Pass	CIT					
				IDPU		T			Bonding measurements	Oct-04	May-05	Pass	UCB					
				Boom		T			Bonding measurements ate Boom Suite I&T (Ground Strap)	Oct-04	May-05	Pass	UCB					
4.24	Electrical Bonding/ Surface Conductivity	Multi-layer thermal blankets shall have all conductive layers electrically bonded together and to chassis ground with a resistance not to exceed 10 ohms Outside layers need to be conductive to meet the < 1v potential differential measurable at any two points on this external surface	EMC - 3.2.3.3/3.2.6.10.4 ICD - 5.2.6					T	APL to build and verify thermal blankets							APL		
4.25	Electrical Bonding/ Blanket Grounding	A mimimum of 2 ground wires is required for each blanket. A ground connection is required within 1 meter of any location on each blanket. The measured resistance between each pair of adjacent ground wires is not to exceed 10 ohms prior to connection to the S/C.	EMC - 3.2.3.3/3.2.6.10.4 ICD - 6.2.4					T	APL to build and verify thermal blankets								APL	

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix														
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments		
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2					
4.26	Electrical Bonding	Doors and other hinged or shafted devices that have an exterior exposure shall have a ground strap, wire, or conductive spring across the hinge or shaft to provide a reliable bond resistance not exceeding 100 ohms to assure a drain path for electrostatic charge.	EMC - 3.2.3.4 ICD - 6.2.4	SIT	T						SIT door ground test				UMd / SS		
				STE	I							STE door ground test	Oct-05	May-05	Pass	UCB / PT	
				SEPT	T							SEPT door ground test	Sep-04	Sep-04	Pass	Kiel	
4.27	Electrical Harness Configuration and Fabrication	Harnesses are to be measured during fab to assure that connector-to-shield bond resistance is no greater than 2.5 mOhms and to confirm continuity between each end is less than 1 ohm.	MRD - 4.6.9.3 EMC - 3.2.5.5	SEP	T						SEP suite harness test	Jul-05	Jul-05	Pass	CIT	UCB can provide support for this test to CIT	
				Boom	T							Boom suite harness test	Oct-04	Oct-04	Pass	UCB	
4.28	Electrostatic Charging/ Surface Resistivity	The maximum variation in surface potential between any 2 points on the external surface of the Instrument shall not exceed 1V. The resistivity of the surface materials shall not exceed 10^8 Ohms/sq.	MRD - 4.6.9.3 EMC - 3.2.6.2	SEPT	T							Aug-05	Aug-05	Pass	Kiel	Test excludes surfaces to be covered with thermal blankets (which are not considered external surfaces). Test measures surface or bulk resistance only. UCB to support CIT for this test.	
				SIT	T								Aug-05	Aug-05	Pass		Umd
				SEPC		T							Aug-05	Aug-05	Pass		CIT
				BOOM				T					Oct-04	Oct-04	Pass		UCB
				IDPU	T					Not external, N/A				UCB			
4.29	CE-01 Conducted Emissions, 100 Hz to 15KHz	IMPACT shall conduct a CE-01 test to demonstrate that the levels of low frequency conducted current emissions on input power and interface lines do not exceed the specified limits: (figure 4.1&2) E) Differential mode test limits are 80dBmicroamps from 100 Hz to 3KHz then decreasing to 50dBmicroA at 15kHz. F) Common mode test limits are 60dBmicroamps from 100 Hz to 10KHz then decreasing to 50dBmicroA at 15kHz	EMC - 4.1														
4.30	CE-01 Conducted Emissions, 100 Hz to 15KHz	IMPACT shall measure differential and common mode currents for the CE-01 test as follows: A) Differential currents are to be measured on the following lines: 1) Power input 2)Power input return 3)True differential current on power, only if 1) or 2) exceeds specification limit. B) Common mode currents are to be measured on the following lines: 1) +28V Power input 2) All other interface lines collectively at each connector. C) Narrowband measurement are to be made with an effective bandwidth not exceeding 120 Hz.	EMC - 4.1							Suite EMC test at UCB subcontractor	Oct-04		Fail*	UCB	Waiver for SWEA Sample Rate (172Hz) on SWEA power line tentatively approved by EMC Committee		
4.31	CE-03 Conducted Emissions, 15KHz to 50MHz	IMPACT shall conduct a CE-03 test to demonstrate that the levels of high frequency conducted current emissions on input power and interface lines do not exceed the specified limits: (figure 4.1&2) B) Differential mode narrowband test limits are 50dBmicroamps from 15kHz decreasing to 20dBmicroA at 2MHz from which it continues at that level to 50MHz. C) Common mode narrowband test limits are 50dBmicroamps from 15kHz decreasing to 20dBmicroA at 2MHz from which it continues at that level to 50MHz.	EMC - 4.2														
4.32	CE-03 Conducted Emissions, 15KHz to 50MHz	IMPACT shall measure differential and common mode currents for the CE-03 test as follows: A) Differential currents are to be measured on the following lines: 1) Power input 2)Power input return 3)True differential current on power, only if 1) or 2) exceeds specification limit. B) Common mode currents are to be measured on the following lines: 1) +28V Power input 2) All other interface lines collectively at each connector. C) Narrowband measurement are to be made with an effective bandwidth not exceeding 120 Hz.	EMC - 4.2								Suite EMC test at UCB subcontractor	Oct-04		Fail*	UCB	Waiver for power converter clock harmonics tentatively approved by EMC committee	
4.33	CE-07 Ripple and Spike Emissions, Time Domain	IMPACT shall conduct a CE-07 test to demonstrate that the broadband levels of conducted ripple and spikes (both voltage and current) on input power and interface lines do not exceed the specified limits as follows: B) Time domain conducted voltage ripple shall not exceed 700 mV p-p fro differential measurements. Common mode voltage shall not exceed 500 mV p-p. C) Time domain conducted current ripple shall not exceed 200 mA p-p fro differential measurements and 50mA p-p for common mode measurements.	EMC - 4.4														
											Suite EMC test at UCB subcontractor	Oct-04		Pass	UCB		

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix												
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2			
4.34	CE-07 Ripple and Spike Emissions, Time Domain	IMPACT shall measure differential and common mode currents and voltages for the CE-07 test as follows: A) Common and Differential mode currents shall be measured on the power lines as described in section 4.1, and the bulk common mode current shall be measured on all interfaces. Differential voltage measurements are to be made between +28V input and return. Common mode voltage measurements shall be made between all 28V input and return lines.	EMC - 4.4							T					
4.35	CS-01 Conducted Susceptibility, 30 Hz to 51 KHz	IMPACT shall conduct a CS-01 test to demonstrate that the performance is not adversely degraded by the presence of low frequency sinusoidal ripple on the primary input power lines. Applicable test parameters are as follows: A) AC sinusoidal ripple shall be applied to the 28V primary power input lines to produce a differential input voltage of 1.0V p-p. B) Ripple current injected into the UUT shall be limited to 5A p-p. C) Ripple frequency shall be swept over the indicated range while monitoring the subsystem for susceptibility. The sweep shall be paused at appropriate intervals to exercise the subsystem and record performance. E) Specific criteria for determining susceptibility shall be documented and approved by the EMC committee prior to testing.	EMC - 4.5							T	Suite EMC test at UCB subcontractor	Oct-04	Fail *	UCB	Some noise in LET detector at 50KHz, not scientifically significant Some noise in MAG at 30Hz. Acceptable at -6dB Some STE noise 30KHz, Acceptable at -6dB Waiver tentatively approved by EMC Committee
4.36	CS-02 Conducted Susceptibility, 49kHz to 400MHz	IMPACT shall conduct a CS-02 test to demonstrate that the performance is not adversely degraded by the presence of high frequency sinusoidal ripple on the primary input power lines. Applicable test parameters are as follows: A) AC sinusoidal ripple shall be applied to the 28V primary power input lines to produce a differential input voltage of 1.0V p-p. B) All test frequencies shall be pulse modulated at 1kHz with 50% duty factor. C) Ripple frequency shall be swept over the indicated range while monitoring the subsystem for susceptibility. The sweep shall be paused at appropriate intervals to exercise the subsystem and record performance. E) Specific criteria for determining susceptibility shall be documented and approved by the EMC committee prior to testing.	EMC - 4.6							T	Suite EMC test at UCB subcontractor	Oct-04	Fail*	UCB	Some LET noise 50-200KHz, peaked at 80KHz; drops to insignificant level at -6dB. Some STE Noise at 50KHz, drops to background at -6dB Waiver tentatively approved by EMC committee
4.37	CS-06 Conducted Susceptibility, Spikes	IMPACT shall conduct a CS-06 test to demonstrate that the performance is not adversely degraded by the presence of transient spikes on the primary input power lines. Applicable test parameters are as follows: A) Peak transient voltage, relative to nominal line voltage, for MIL-STD-461B spike #1(slow) and spike #2(fast) shall be 20V differential, 10V return-to-chassis or B) Both positive and negative spikes are to be applied. C) These spikes are to be applied a) differentially to the primary power input lines and b) between primary power input return and chassis. D) Spikes shall be applied at a variable rate from 1 to 5 spikes per second for a duration of at least 2 minutes while monitoring the subsystem for susceptibility. E) Specific criteria for determining susceptibility shall be documented and approved by the EMC committee prior to testing.	EMC - 4.7							T	Suite EMC test at UCB subcontractor	Oct-04	Fail*	UCB	Nothing with shorter pulses Some detector counts with longer pulses 1553 errors with longer pulses (handled OK) Waiver tentatively approved by EMC Committee
4.38	RE-01 Radiated Emissions, Magnetic Field, 100Hz to 49 kHz	IMPACT shall conduct a RE-01 test to demonstrate that the levels of low frequency radiated magnetic field emissions from the operating subsystem do not exceed the specified limits: A) Emission limits are 120dB pT (1000 gamma) starting at 100 Hz then decreasing to 20dB pT (10 milligamma) at 32 kHz from which it continues at the same level to 49 kHz. Data will be acquired to 51kHz. B) The subsystem is to be scanned on all sides to determine maximum emission levels.	EMC - 4.8							T	Suite EMC test at UCB subcontractor	Oct-04	Fail*	UCB	See MAG Drive and harmonics See SEP Serial Interface harmonics Waiver tentatively approved by EMC Committee
4.39	RE-02 Radiated Emissions, Electric Field, 14 kHz to 10 GHz	IMPACT shall conduct a RE-02 test to demonstrate that the levels of low frequency radiated electric field emissions from the operating subsystem do not exceed the specified limits: B) Narrowband emission limits are 110 dB microV/m from 14 kHz to 20 MHz then increasing to 70dBmicroV/m at 10GHz. Also, in the band 7180 +/- 25MHz the limit is 15dB microV/m. C) Broadband emission limits are 110 dB microV/m/MHz at 14 kHz decreasing to 65 dBmicroV/m/MHz at 200 MHz then increasing to 80 dB microV/m/MHz at 1.0 GHz.	EMC - 4.9							T	Suite EMC test at UCB subcontractor	Oct-04	Fail*	UCB	SEP, IDPU Processor clock Harmonics, 24MHz - 1.4GHz Waiver tentatively approved by EMC Committee

v1.9		23-Sep-05		STEREO/ IMPACT Requirements Verification Matrix														
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Verification Description	Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments		
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory		FM#1	FM#2					
4.40	RE-02 Radiated Emissions, Electric Field, 14 kHz to 10 GHz	1) IMPACT is required to record data, in addition to the above, over the frequency range from 2 kHz to 14 kHz... 2) Instrument covers must be open during radiated emission and susceptibility testing. RF transparent covers must be supplied to prevent contamination.	EMC - 4.9							T								
4.41	RS-03 Radiated Susceptibility, 14 kHz to 15 GHz	IMPACT shall conduct a RCS-U test to demonstrate that the performance of the subsystem is not adversely degraded by the presence of high frequency radiated electric fields. Applicable test parameters are as follows: A) Over the frequency range from 14 kHz to 1.0 GHz, the subsystem shall be irradiated with an electric field intensity of 10 V/m. B) Over the frequency range from 1.0 GHz to 15 GHz, the subsystem shall be irradiated with an electric field intensity of 20 V/m. C) In the bands 2.2 to 2.3 GHz, 5.5 to 5.9 GHz, and 8.4 to 8.5 GHz the applied field shall be 40 V/m. D) Test frequencies at and above 100MHz shall be pulse modulated at 1kHz with a 50% duty factor. Lower frequencies shall be CW. E) Frequency shall be manually swept over the indicated range while monitoring the subsystem for susceptibility. The sweep shall be paused at appropriate intervals to exercise the subsystem and record performance. F) If susceptibility is encountered, then threshold levels are to be determined and recorded. G) Specific criteria for determining susceptibility shall be determined by the EMC committee.	EMC - 4.10							T	Suite EMC test at UCB subcontractor	Oct-04		Fail*	UCB	Some detector counts 400MHz-4GHz, background by -6 - -12dB STE counts at up to 9GHz, including at transmit band (8.5GHz) STE counts in transmit band only with AM modulation, not FM Waiver tentatively approved by EMC committee		
4.42	Acceptance Tests	Certification tests require that 1 item from every instrument set to be tested. Second instruments are to be tested for Conducted Emissions as described below. Testing will consist of narrowband common mode and differential mode conducted emissions on power and power return lines from 15 kHz to 40 MHz using the same limits specified in section 4.2.	EMC - 8.1	SEP						T		SEP Suite FM2 EMC test @ CIT		Aug-05	Fail	CIT / UCB	SIT to SEP harness 25KHz noise under investigation	
				IDPU						T			IDPU / MAG / STE-U FM2 EMC test @ UCB		Jun-05	Pass	UCB	Retest
				SWEA							T			SWEA/STE-D FM2 EMC Test @ UCB		May-05	Pass	UCB
5.0		C&DH IF REQUIREMENTS																
C&DH IF Requirements																		
5.1	Distribution of S/C Time and Status	The IMPACT/PLASTIC IDPU shall be designed to accept a 1553 message once per second on subaddress R-1. This message will contain the following data: S/C UTC time, S/C status, Imminent HGA motion, Observatory fine pointing, Off Pointing, SSR Partition %Full. Table 4-7 shows the format of this message. The IMPACT/PLASTIC IDPU shall be designed to accept the "synch with data word" mode code and compute UTC.	ICD - 4.4.2.1 Table 4-7	IDPU							T		IDPU CPT	Oct-04	Dec-05	Pass	UCB	
5.2	Collection of Instrument Status	The IMPACT/PLASTIC IDPU shall be designed to have the S/C collect an "Instrument Status" message once per second using subaddress T-1. Table 4-8 shows the format of this message.	ICD - 4.4.2.2 Table 4-8	IDPU							T		IDPU CPT	Oct-04	Dec-05	Pass	UCB	

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix														
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments		
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2					
5.3	Distribution of Instrument Command Packets	<p>1.The IMPACT/PLASTIC IDPU shall receive commands from the C&DH in the form of CCSDS telecommand packets. Maximum telecommand packet length, including the header, is 1088 bytes.</p> <p>2.The IMPACT/PLASTIC IDPU shall be able to process CCSDS telecommand packets broken up into fixed length portions, known as Fixed-Length Transfer Containers (FLTCs).</p> <p>3.The IMPACT/PLASTIC IDPU shall be able to retrieve FLTCs from subaddress R-3.</p> <p>4. The IMPACT/PLASTIC IDPU shall be able to process an FLTC according to the format in table 4-9. Each FLTC will be 64 bytes long.</p> <p>5.The IMPACT/PLASTIC IDPU shall be able to process telecommands that span multiple FLTCs.</p> <p>6. The IMPACT/PLASTIC IDPU shall be able to process FLTCs that contain one or more complete or partial CCSDS TC packets.</p> <p>7. The IMPACT/PLASTIC IDPU shall be able to process FLTCs that contain fill data at the end of an FLTC.</p> <p>8. The IMPACT/PLASTIC IDPU shall be able to process idle FLTCs that contain only fill data.</p> <p>12. The IMPACT/PLASTIC IDPU shall be able to process FLTCs that contain an invalid APID (all ones) as fill data.</p> <p>13. The IMPACT/PLASTIC IDPU shall be able to process</p>	ICD - 4.4.2.3 Table 4-9			T							Oct-04	Dec-05	Pass	UCB	
5.4	Collection of Instrument Telemetry Packets	<p>1. The IMPACT/PLASTIC IDPU shall send tm data to the (S/C) C&DH computer in the form of CCSDS packets.</p> <p>In addition to the required CCSDS header, each (telemetry) packet shall contain a 5-byte secondary header containing a UTC time value representing the collection time of the data in the packet. The length of each CCSDS telemetry packet, including headers, shall be 272 bytes.</p> <p>2. IMPACT/PLASTIC IDPU shall maintain a counter in subaddress T-2 to indicate when new data has been written to the buffer. The IDPU shall increment this counter (Telemetry Packet Data Available Counter) by 1 every time it writes a new telemetry packet to the buffer.</p> <p>3. IMPACT/PLASTIC IDPU shall ensure that the telemetry buffer contains valid data before incrementing the TBDAC</p> <p>4. IMPACT/PLASTIC IDPU shall not change the TBDAC, nor change the data in the buffer until the (S/C) C&DH has read the data.</p> <p>5.IMPACT/PLASTIC IDPU shall store 64 bytes of the telemetry packet in subaddresses T-3 thru T-7, and the remainder 16 bytes in T-8.</p> <p>6.IMPACT/PLASTIC IDPU shall write a new (tm) packet and a new TBDAC value to the (T-2 thru T-7 subaddress) 1553 space no later than 10msec (ideally 1msec).</p> <p>The IMPACT/PLASTIC IDPU shall support the Mode Code transactions defined in table 4-10</p>	ICD - 4.4.2.4			T							Oct-04	Oct-04	Pass	UCB	
5.5	Mode Codes for 1553 Bus Diagnostics		ICD - 4.4.2.5.1 Table 4-10			T							Oct-04	Oct-04	Pass	UCB	
6.0	CONTAMINATION REQUIREMENTS																
6.1	Surface Cleanliness Requirement	Unless stated in Table 3.2-1, external surfaces of all IMPACT components that are mounted externally on the spacecraft, shall meet a surface cleanliness level of 300 A (or equivalent PAC) per MIL-STD-1246, with integration activities at UCB shall take place in Class 10,000 cleanroom environment, and purge shall be maintained at all times except when interruptions are explicitly permitted. The IDPU and any other items which will be located inside the STEREO spacecraft shall meet the STEREO spacecraft requirement of level 300 A (or equivalent	CC - 4.1 ICD - 7.2.1	SEPT	T								Aug-05	Aug-05	Pass	Kiel	
				SIT	T							Aug-05	Aug-05	Pass	UMd		
				SEPC		T						Aug-05	Aug-05	Pass	CIT		
				BOOM			T					Mar-05	May-05	Pass	UCB		

v1.9		23-Sep-05	STEREO/ IMPACT Requirements Verification Matrix													
Req#	Parameter/ Req Title Section	Requirement	Document	Level of Assembly/Ver Method							Completion Date		Results (Pass/Fail)	Responsible Organization	Notes / Comments	
				Subassembly	Assembly	Instrument Component	SEP Suite	Boom Suite	IMPACT Suite	Observatory	FM#1	FM#2				
		PAC) per MIL-STD-1246. Thermal Control surfaces shall not exceed Level B per MIL-STD-1246 at End-of-Life.		IDPU	T							Mar-05	May-05	Pass	UCB	
6.2	Materials List	It is required by the IMPACT project that a material list be provided for each subsystem for approval by UCB prior to fabrication. The list is to include material name, description, manufacturer, and usage. The characteristics of total mass loss and condensable volatile condensable materials are also to be included on this list. NASA Reference Publication 1124 or MAPTIS will be consulted to determine that all non-metallic materials have a Total Mass Loss (TML) of 1.0% or less and Collected Volatile Condensable Material (CVCM) of 0.1% or less. Acceptability of materials for flammability and odor will be determined from document ASTM E695.	CC - 8.1 ICD - 7.2.2	SEPT	X									Pass	Kiel	Preliminary lists provided at PDR, "Final" lists provided at CDR; updated lists as required
				SIT	X									Pass	UMd	
				HET	X					One waiver approved				Pass	GSFC	
				SEPC	X					Sep Central / LET list				Pass	CIT	
				BOOM	X					Boom / IDPU / STE / LVPS List. One Waiver approved				Pass	UCB	
				MAG	X									Pass	GSFC	
				SWEA	X									Pass	CESR	
6.3	Outgassing Certification	Prior to acceptance to being integrated on STEREO, all payload components shall undergo a thermal vacuum certification with a Quartz Crystal Microbalance (QCM). This certification may be performed with on separate components of IMPACT or on all the components as an assembly. It shall be performed in accordance with paragraph 6.3.2.	CC - 8.3.4 ICD - 7.2.2	SEPT	T					During thermal balance test @ GSFC	Feb-05	Feb-05	Pass	Kiel		
				SIT	T					During thermal balance test	Feb-05	Mar-05	Pass	UMd		
				SEPC		T					Jul-05	Jul-05	Pass	CIT		
				BOOM			T				Jun-04	Oct-04	Pass	UCB		
				SWEA	T						Feb-05	May-05	Pass	UCB	SWEA FM2 had some difficulty - see thermal vac test report, ultimately approved	
				IDPU	T						Feb-05	Feb-05	Pass	UCB		
SOFTWARE REQUIREMENTS																
7.0	Software	Each instrument and the IMPACT/PLASTIC IDPU must verify the requirements as described in their Software Requirements Documents and Software Development Plans.	IPF ICD	SEPC		T				SEP Central Software Acceptance Test	Jul-05		Pass	CIT		
				LET	T					LET Software Acceptance Test	Aug-05		Pass	CIT		
				HET	T					HET Software Acceptance Test	Sep-05		Pass	GSFC		
				SIT	T					SIT Software Acceptance Test	May-05		Pass	GSFC		
				IDPU	T					IDPU Boot Software Acceptance Test	Oct-03		Pass	UCB	Repeated subsections at Spacecraft ETU Interface test, 2003-10-28	
				IDPU	T					IDPU Instrument Software Acceptance Test	Feb-05		Pass	UCB	IMPACT software rev 25, includes PLASTIC rev 2.6, (not final)	